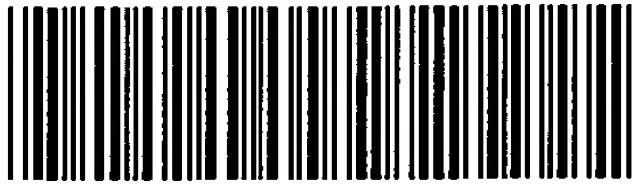


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/627,781	NAKAHARA ET AL.	
	Examiner	Art Unit	
	Thien D. Tran	2665	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	503	10/1/2005	TT
	203	10/1/2005	TT
	210	10/1/2005	TT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPGPUB, USPAT, USOCR, EPO, DERWENT), 370/203, 206, 207, 210, 503, 516.	10/1/2005	TT